

Notice of References Cited

Application/Control No.

10/032,729

Applicant(s)/Patent Under
Reexamination
CHEN ET AL.

Examiner

John L. Shew

Art Unit

2616

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0154634 A1	10-2002	Basso et al.	370/390
*	B	US-6,658,014 B1	12-2003	Tezuka, Yasuo	370/412
*	C	US-4,809,269	02-1989	Gulick, Dale E.	370/462
*	D	US-6,269,081 B1	07-2001	Chow et al.	370/241
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S		07-2001			
	T	US-				

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages			
	U				
	V				
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.